Electrical control of magnetism in semiconductors

(Fumihiro Matsukura)

Abstract :

By utilizing the nature of carrier-induced ferromagnetism [1], the Curie temperature $T_{\rm C}$ of ferromagnetic semiconductors (In,Mn)As and (Ga,Mn)As can be modulated electrically through the change of their hole concentration (Δp of p) in field effect transistor (FET) structures [2-4]. In this work, we have investigated $T_{\rm C}$ and its change of the magnitude, $\Delta T_{\rm C}$, of (Ga,Mn)As channel as a function of its thickness t and Mn composition x.

(Ga,Mn)As layers with perpendicular magnetic easy axis were grown by molecular beam epitaxy on GaAs/AlGaAs/InGaAs/GaAs buffer layer on semi-insulating GaAs (001) substrate. We prepared (Ga,Mn)As with thickness t = 3.5, 4.0, 4.5, and 5.0 nm with a fixed x = 0.065, and (Ga,Mn)As with t = 4.0 or 4.5 nm with various x from 0.027-0.200. The samples were processed into Hall-bar geometry with Al₂O₃ or HfO₂ gate insulator, and topmost Cr/Au metal gate electrode. We measured the temperature dependence of anomalous Hall resistance to determine $T_{\rm C}$ under gate electric fields |E| up to 5 MV/cm.

We found that $T_{\rm C}$ increases, while magnitude of $\Delta T_{\rm C}$ decreases, with increasing *t* as well as *x*, and that there exists linear relationship between $\Delta T_{\rm C}/T_{\rm C}$ and $\Delta p/p$.

The work done with D. Chiba, Y. Nishitani, M. Endo, and H. Ohno

[1] T. Dietl, H. Ohno, F. Matsukura, J. Cibert, and D. Ferrand, Science 287, 1019 (2000).

[2] H. Ohno, D. Chiba, F. Matsukura, T. Omiya, E. Abe, T. Dietl, Y. Ohno, and K. Ohtani, Nature **408**, 944 (2000).

[3] D. Chiba, M. Yamanouchi, F. Matsukura, and H. Ohno, Science 301, 943 (2003).

[4] D. Chiba, F. Matsukura, and H. Ohno, Appl. Phys. Lett. 89, 162505 (2006).